

MOS FIELD EFFECT TRANSISTOR **2SK3455**

SWITCHING N-CHANNEL POWER MOS FET

DESCRIPTION

The 2SK3455 is N-channel DMOS FET device that features a low gate charge and excellent switching characteristics, designed for high voltage applications such as switching power supply, AC adapter.

ORDERING INFORMATION

PART NUMBER	PACKAGE			
2SK3455	Isolated TO-220			

FEATURES

•Low gate charge

 $Q_G = 30 \text{ nC TYP.}$ ($V_{DD} = 400 \text{ V}$, $V_{GS} = 10 \text{ V}$, $I_D = 12 \text{ A}$)

- •Gate voltage rating ±30 V
- •Low on-state resistance

RDS(on) = 0.60Ω MAX. (VGS = 10 V, ID = 6.0 A)

- Avalanche capability ratings
- •Isolated TO-220 package

ABSOLUTE MAXIMUM RATINGS ($T_A = 25$ °C)

Drain to Source Voltage (VGS = 0 V)	VDSS	500	V
Gate to Source Voltage (VDS = 0 V)	Vgss	±30	V
Drain Current (DC) (Tc = 25°C)	ID(DC)	±12	Α
Drain Current (Pulse) Note1	D(pulse)	±36	Α
Total Power Dissipation (T _A = 25°C)	P _{T1}	2.0	W
Total Power Dissipation (Tc = 25°C)	Рт2	50	W
Channel Temperature	Tch	150	°C
Storage Temperature	T _{stg}	−55 to +150	°C
Single Avalanche Current Note2	las	12	Α
Single Avalanche Energy Note2	Eas	103	mJ

Notes 1. PW \leq 10 μ s, Duty Cycle \leq 1%

2. Starting Tch = 25°C, VDD = 150 V, Rg = 25 Ω , Vgs = 20 \rightarrow 0 V

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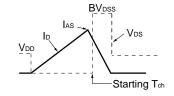


ELECTRICAL CHARACTERISTICS (TA = 25°C)

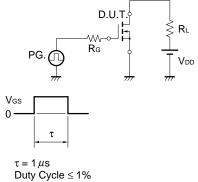
CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Zero Gate Voltage Drain Current	loss	V _{DS} = 500 V, V _{GS} = 0 V			100	μΑ
Gate Leakage Current	lgss	Vgs = ±30 V, Vps = 0 V			±100	nA
Gate Cut-off Voltage	V _{GS(off)}	V _{DS} = 10 V, I _D = 1 mA	2.5		3.5	V
Forward Transfer Admittance	yfs	V _{DS} = 10 V, I _D = 6.0 A	2.0			S
Drain to Source On-state Resistance	RDS(on)	Vgs = 10 V, ID = 6.0 A		0.50	0.60	Ω
Input Capacitance	Ciss	V _{DS} = 10 V		1620		pF
Output Capacitance	Coss	V _G S = 0 V		250		pF
Reverse Transfer Capacitance	Crss	f = 1 MHz		10		pF
Turn-on Delay Time	td(on)	V _{DD} = 150 V, I _D = 6.0 A		24		ns
Rise Time	tr	V _{GS} = 10 V		18		ns
Turn-off Delay Time	td(off)	R _G = 10 Ω		50		ns
Fall Time	tf			15		ns
Total Gate Charge	Qg	V _{DD} = 400 V		30		nC
Gate to Source Charge	Qgs	V _G S = 10 V		9		nC
Gate to Drain Charge	Q _{GD}	ID = 12 A		11		nC
Body Diode Forward Voltage	VF(S-D)	IF = 12 A, VGS = 0 V		1.0		٧
Reverse Recovery Time	trr	IF = 12 A, VGS = 0 V		1.5		μs
Reverse Recovery Charge	Qrr	di/dt = 50 A/ μs		11		μC

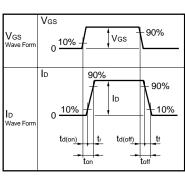
TEST CIRCUIT 1 AVALANCHE CAPABILITY

$\begin{array}{c} \text{D.U.T.} \\ \text{Rg} = 25 \Omega \\ \text{Ves} = 20 \rightarrow 0 \text{ V} \\ \end{array}$

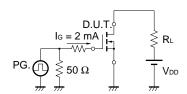


TEST CIRCUIT 2 SWITCHING TIME





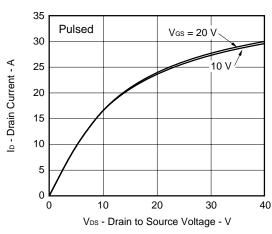
TEST CIRCUIT 3 GATE CHARGE



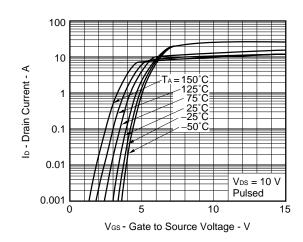


TYPICAL CHARACTERISTICS (TA = 25°C)

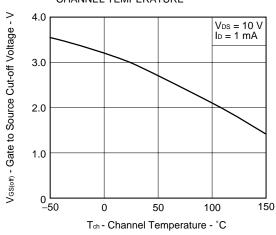




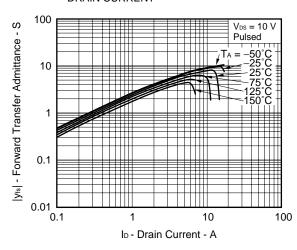
FORWARD TRANSFER CHARACTERISTICS



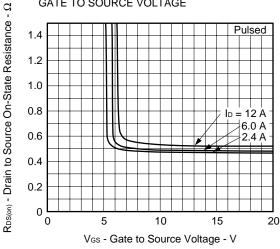
GATE TO SOURCE CUT-OFF VOLTAGE vs. CHANNEL TEMPERATURE



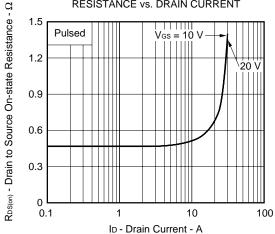
FORWARD TRANSFER ADMITTANCE vs. DRAIN CURRENT

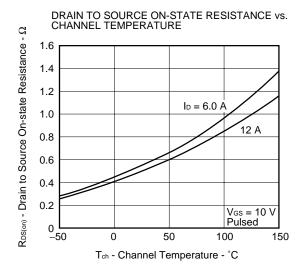


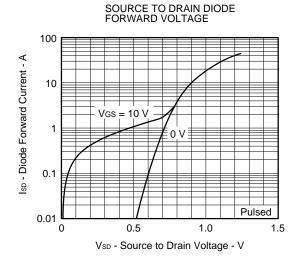
DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE

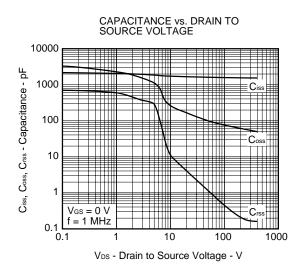


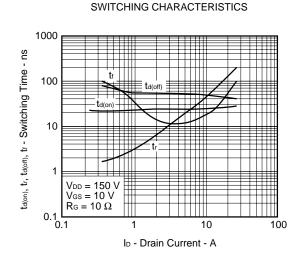
DRAIN TO SOURCE ON-STATE RESISTANCE vs. DRAIN CURRENT

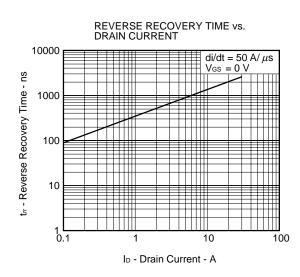


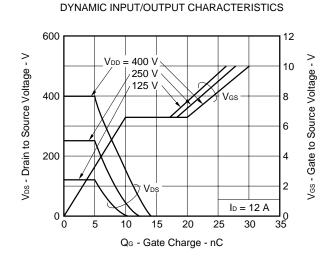




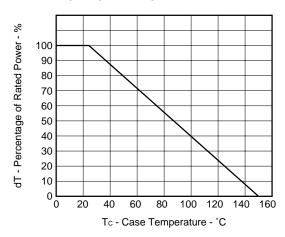




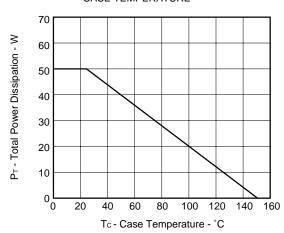




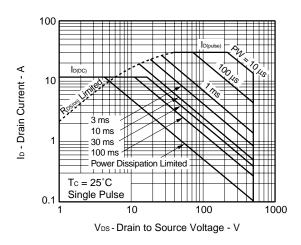
DERATING FACTOR OF FORWARD BIAS SAFE OPERATING AREA



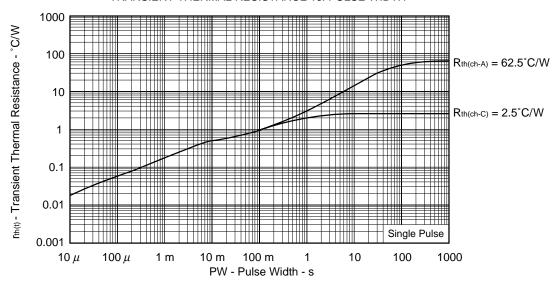
TOTAL POWER DISSIPATION vs. CASE TEMPERATURE



FORWARD BIAS SAFE OPERATING AREA

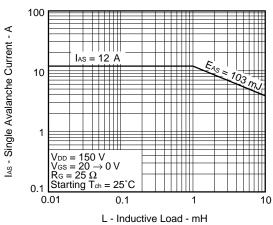


TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH

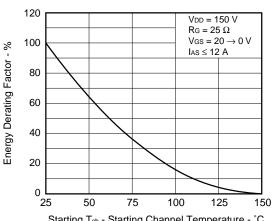


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SINGLE AVALANCHE CURRENT vs. INDUCTIVE LOAD



SINGLE AVALANCHE ENERGY **DERATING FACTOR**

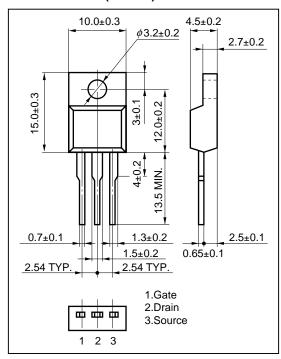


Starting Tch - Starting Channel Temperature - °C

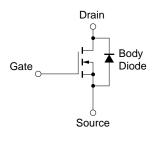


PACKAGE DRAWING (Unit: mm)

Isolated TO-220 (MP-45F)



EQUIVALENT CIRCUIT



Remark Strong electric field, when exposed to this device, can cause destruction of the gate oxide and ultimately degrade the device operation. Steps must be taken to stop generation of static electricity as much as possible, and quickly dissipate it once, when it has occurred.

Data Sheet D14757EJ1V0DS 7

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